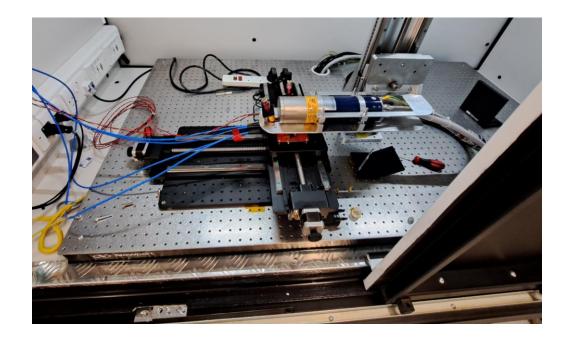


MIr1 CML test chip irradiation studies.

Comparison of results using X-ray sets at CERN and Daresubury



Test setup at Daresbury Lab.

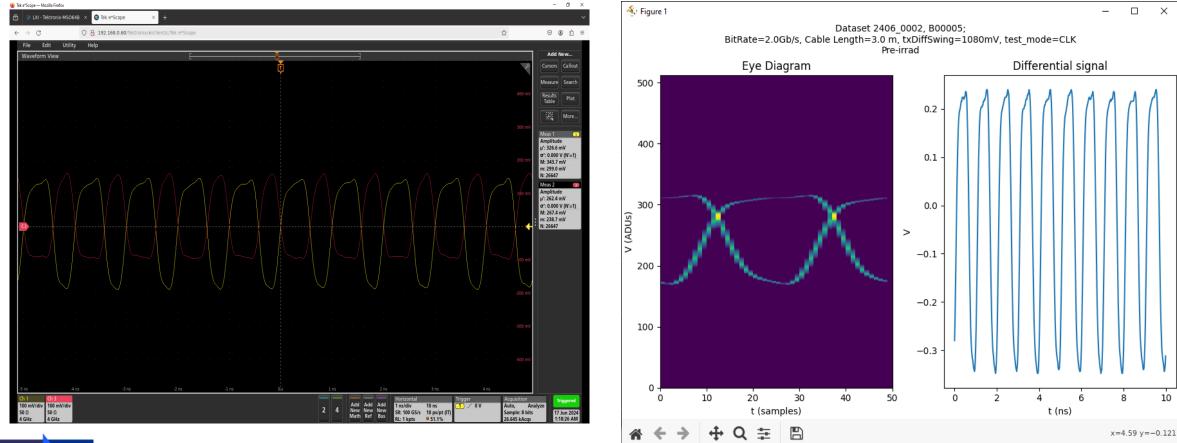


DUT in X-ray set at DL



- Test signal supplied by KCU105.
- 2 Gbits/s fast clock pattern.
- Measured using MSO64B DSO.
- Data taking automated using Python
- VDD1V2=1.2V
- VDD2V5=2.5V
- 3 devices irradiated at CERN and 3 at Daresbury using these settings.

B00005 pre-irradiation





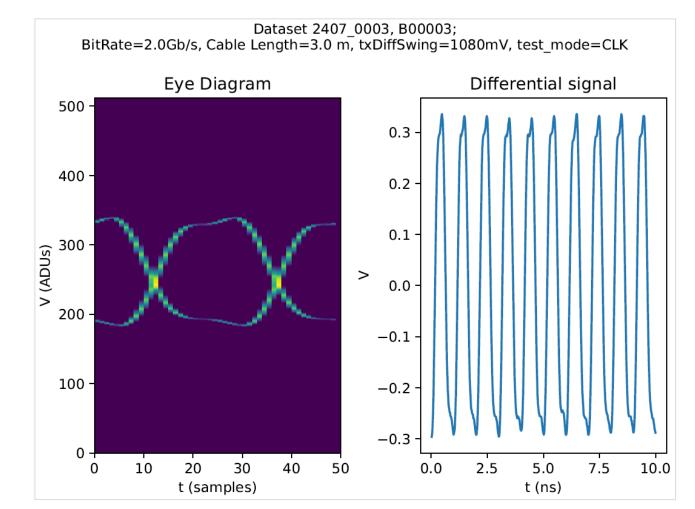
Eye Diagram B00003

- Eye diagram from B00003
- Note more symmetric mark/space ratio preirradiation.

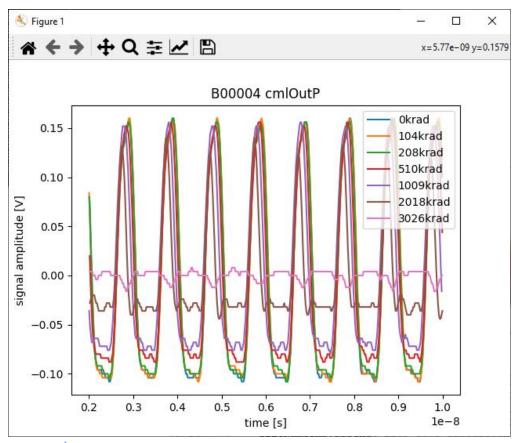
Science and

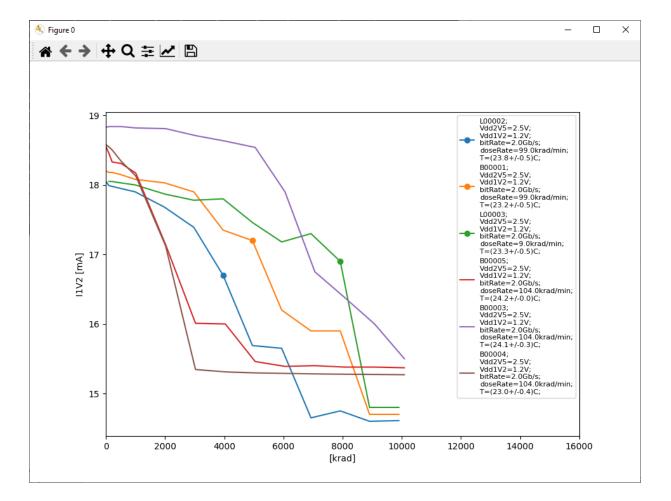
Technology

Facilities Council



Degradation of output with irradiation



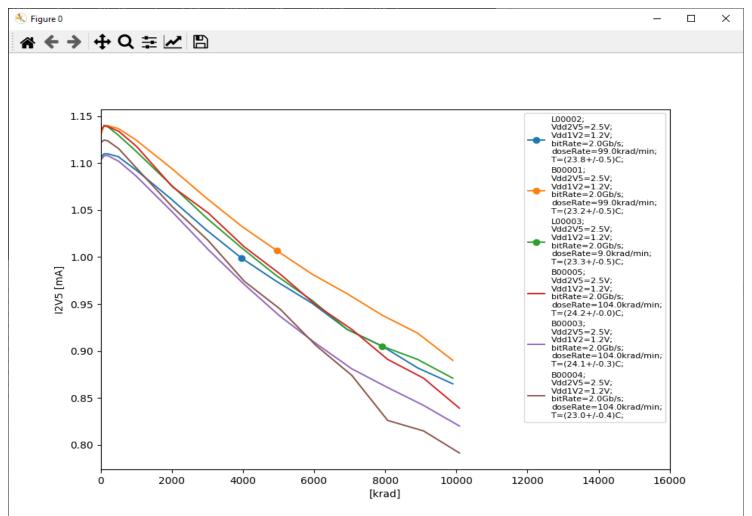




Current from 2V5 rail

- Data from devices irradiated at CERN are shown with circular markers (L00002, B00001 & L00003)
- Devices irradiated at Daresbury are B00005, B00003 & B00004 – no markers.





Conclusions

- Variation dose tolerated before device stops working seems to be from part to part spread.
- Decrease in current drawn from VDD2V5 with dose seems similar between different devices.
- This data appears reproducible between irradiations at CERN and Daresbury Laboratory.

